

**Search Notes**

Application/Control No.

10/659,591

Examiner

M. Lee

Applicant(s)/Patent under  
Reexamination

PAIK ET AL.

Art Unit

2622

**SEARCHED**

Class	Subclass	Date	Examiner
348	678, 725, 726, 735,	7/3/2007	ML
375	345		
455	234.1		
	234.2		
	239.1		
	240.1		
	241.1		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference search history printout		7/3/2007	ML

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/3/2007	ML